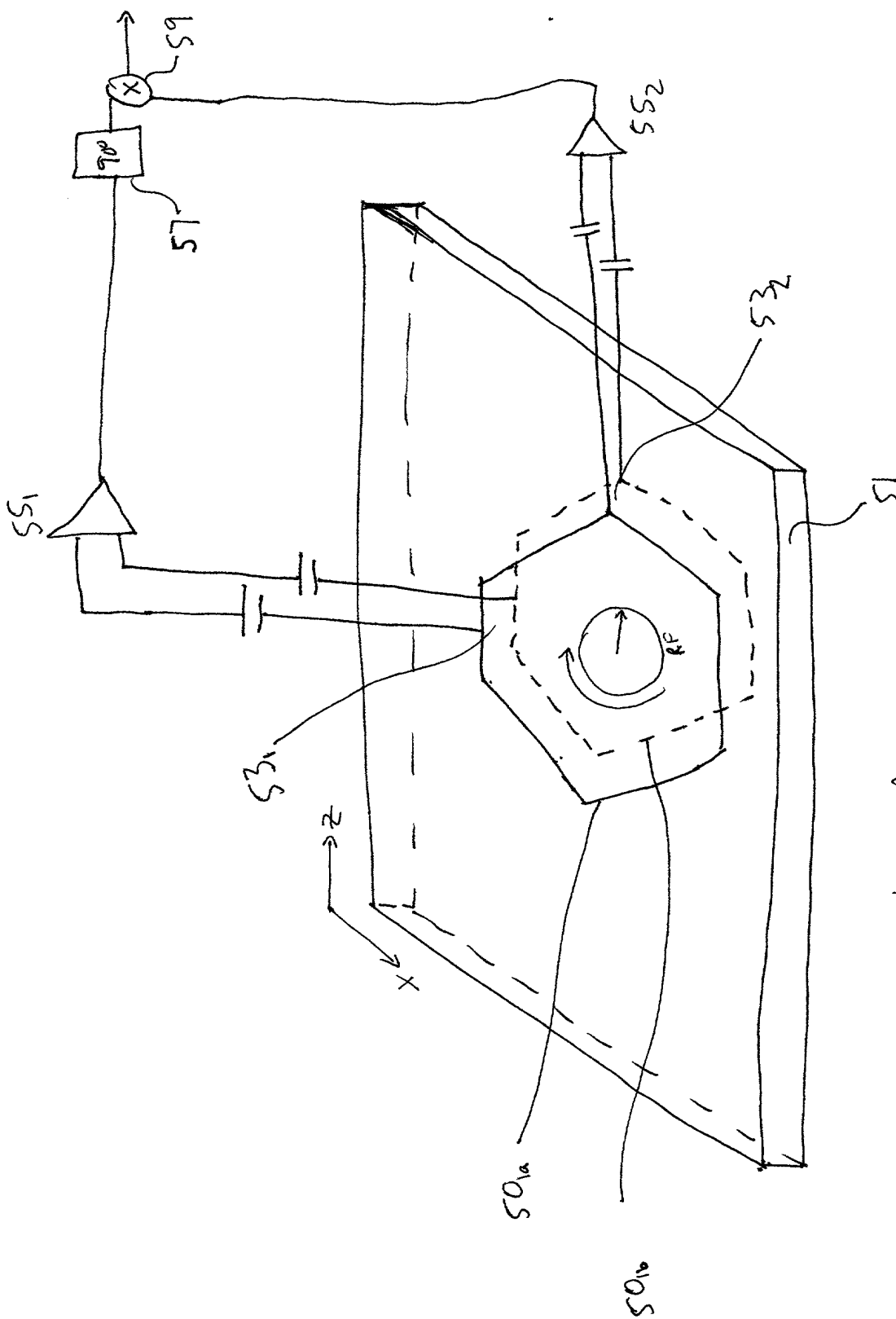


FIG. 2



F16.3A

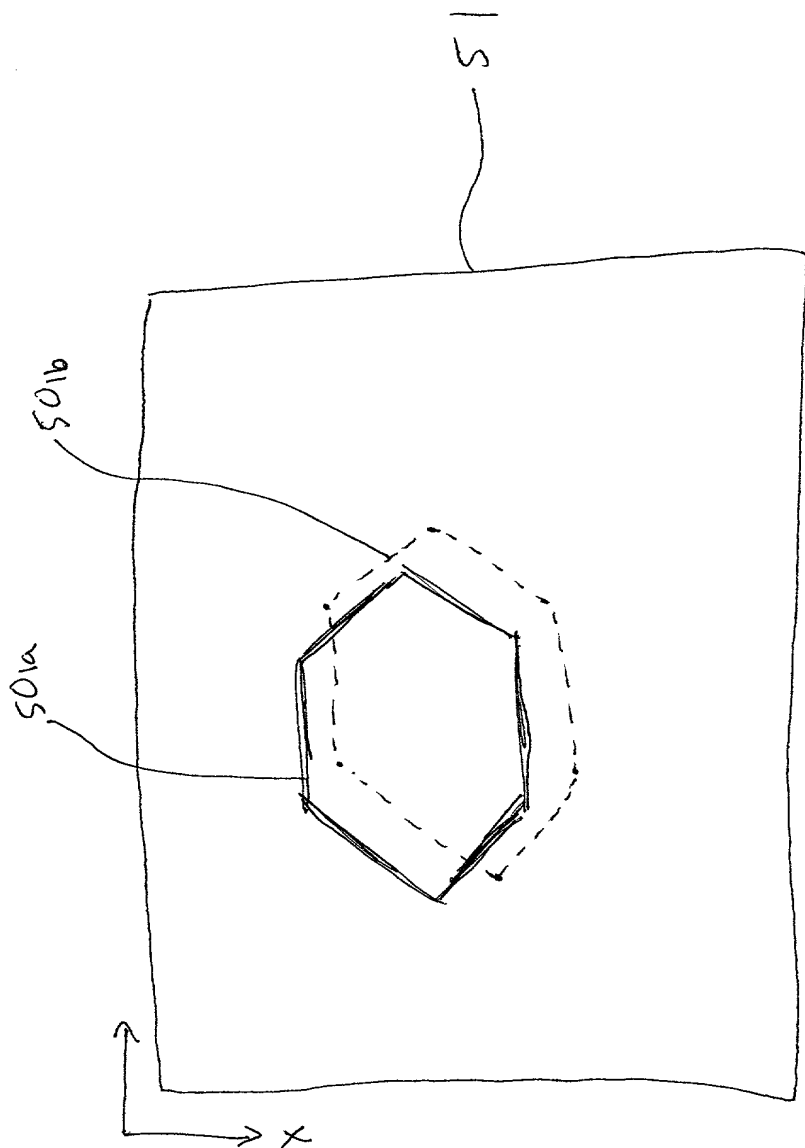


FIG. 3B

FIG. 16.4 is a perspective view of a device 15, showing a top surface 16, a bottom surface 17, and a side surface 18. The device 15 is a rectangular block with a central opening 19. The opening 19 is a rectangular hole passing through the device 15. The top surface 16 is the upper face of the device 15, and the bottom surface 17 is the lower face. The side surface 18 is one of the vertical faces of the device 15. The opening 19 is located in the center of the top surface 16 and extends through the device 15 to the bottom surface 17.

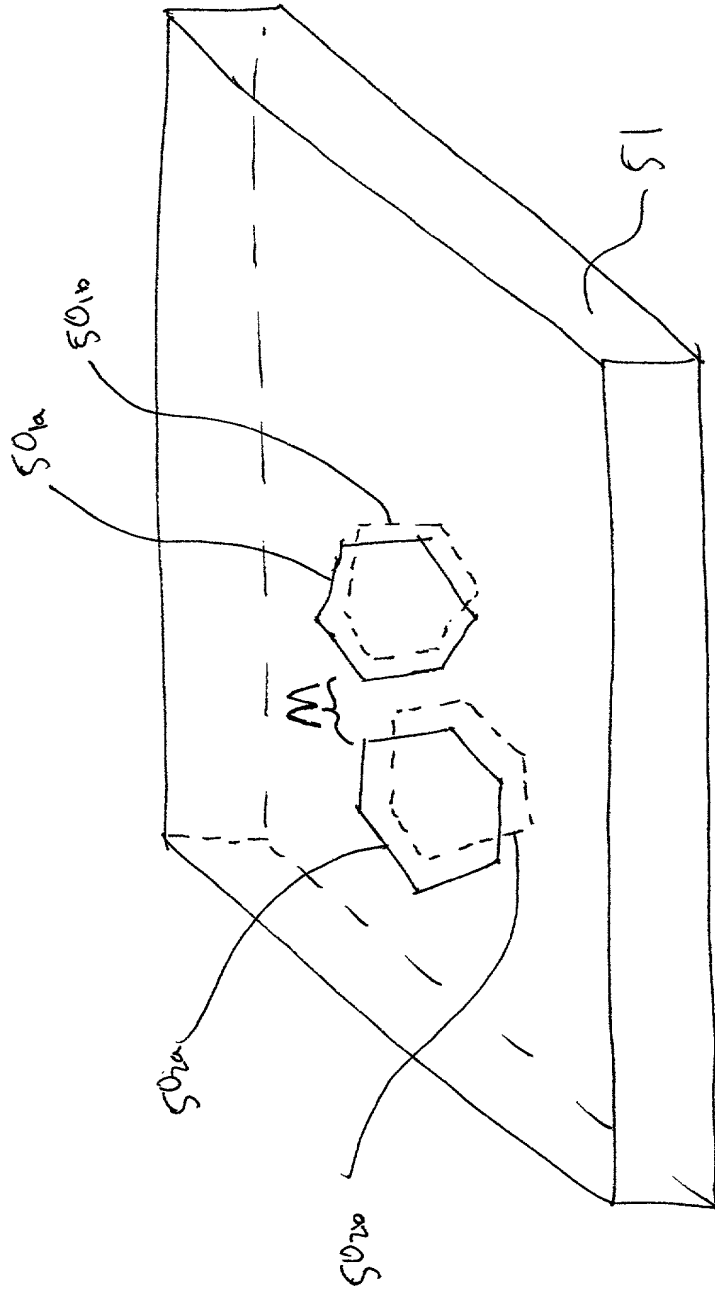


FIG. 4

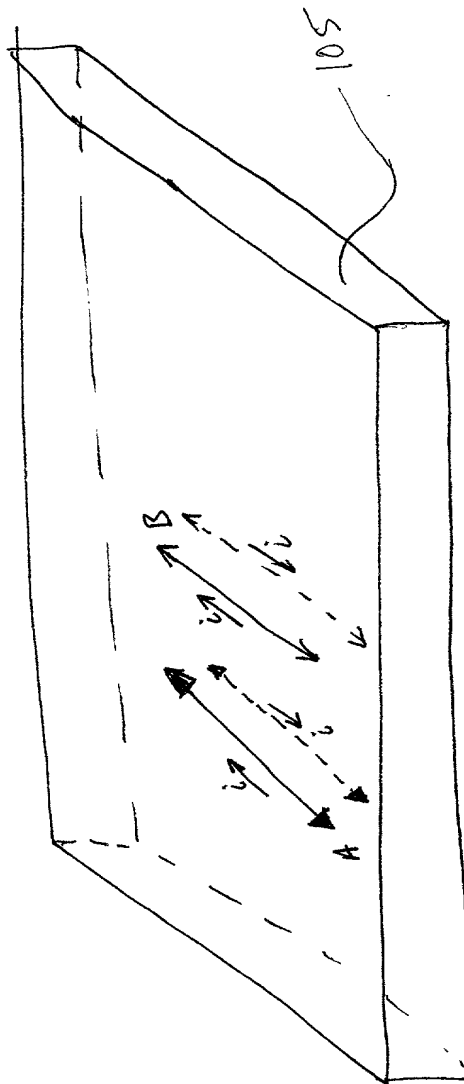
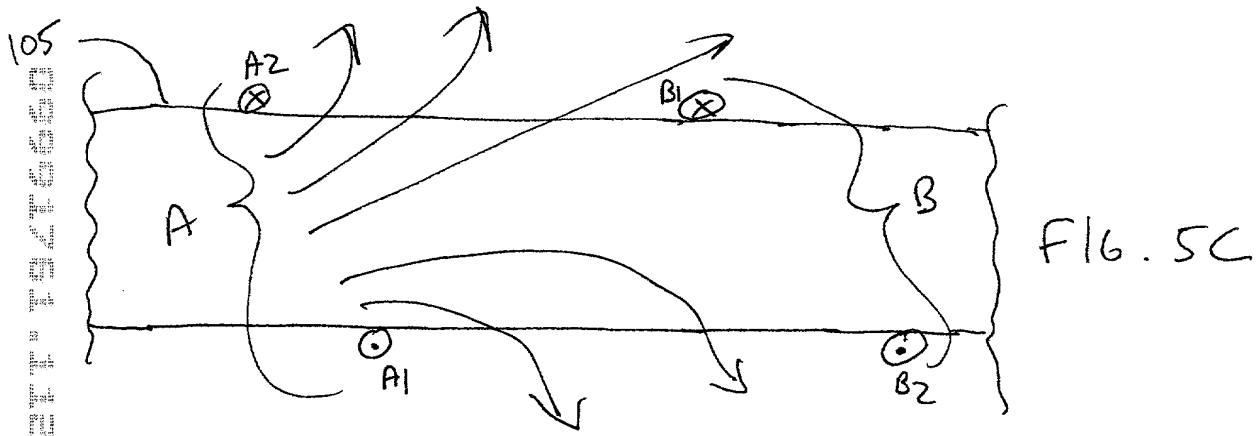
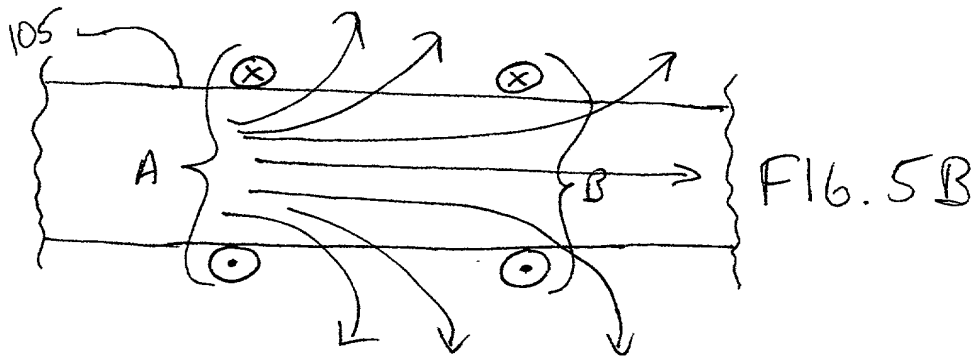


FIG. 5A



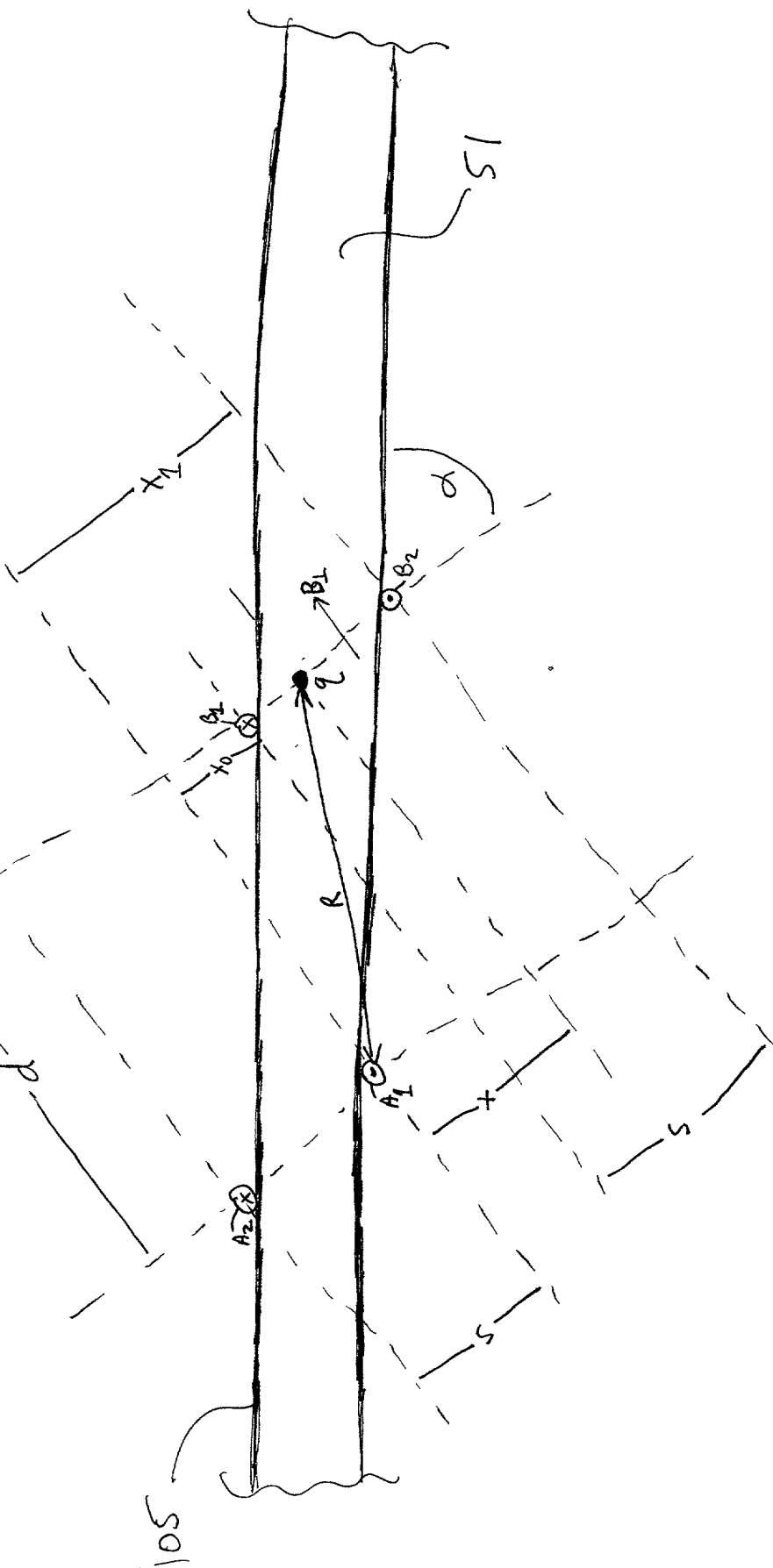


FIG. 5D



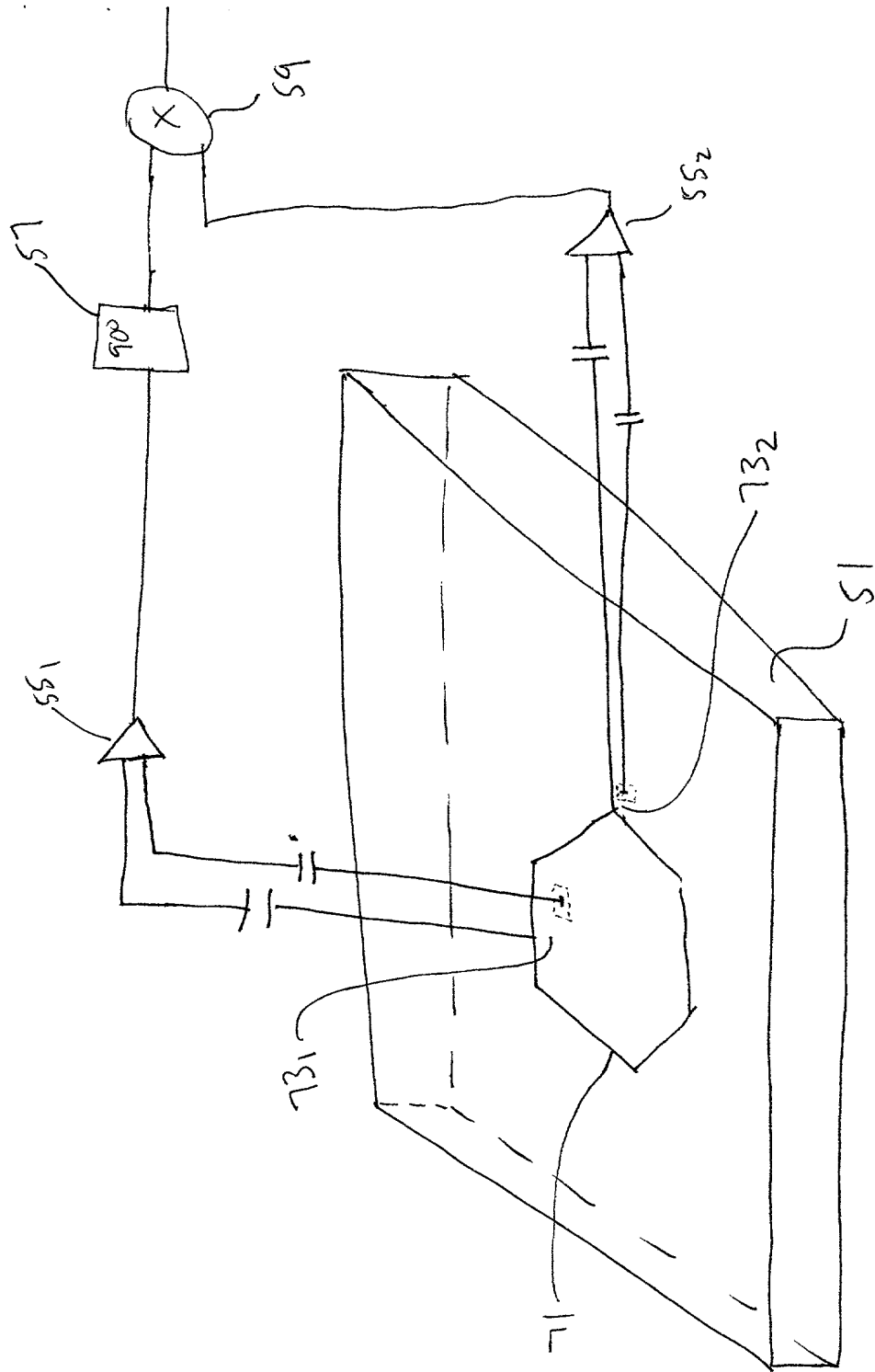


FIG. 6

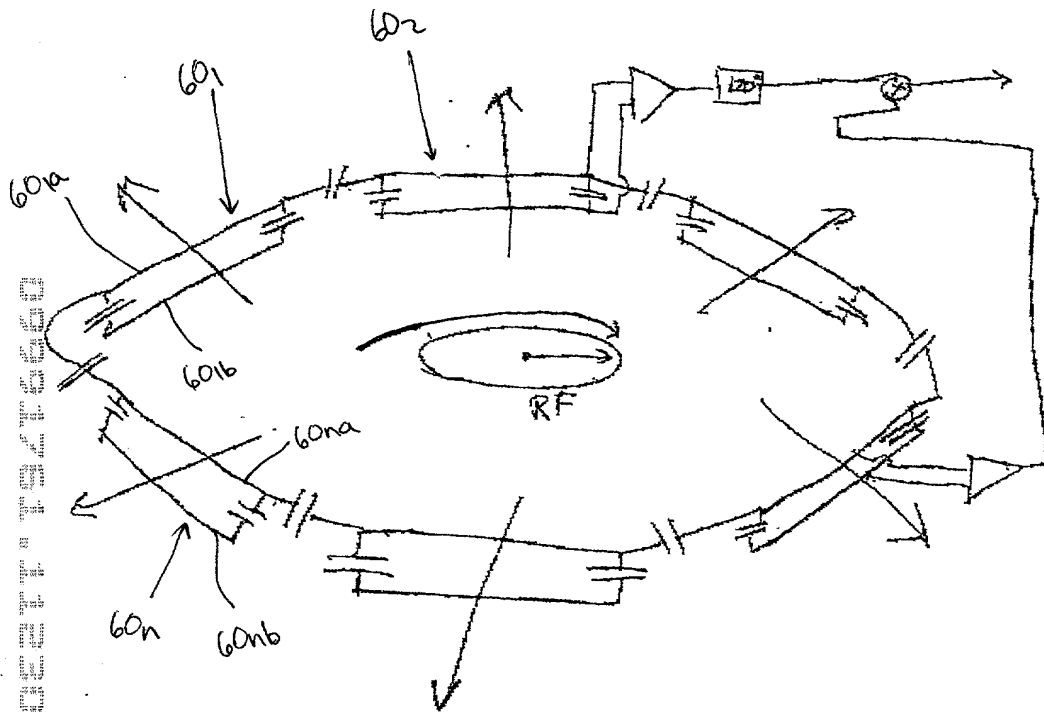


FIG. 7A

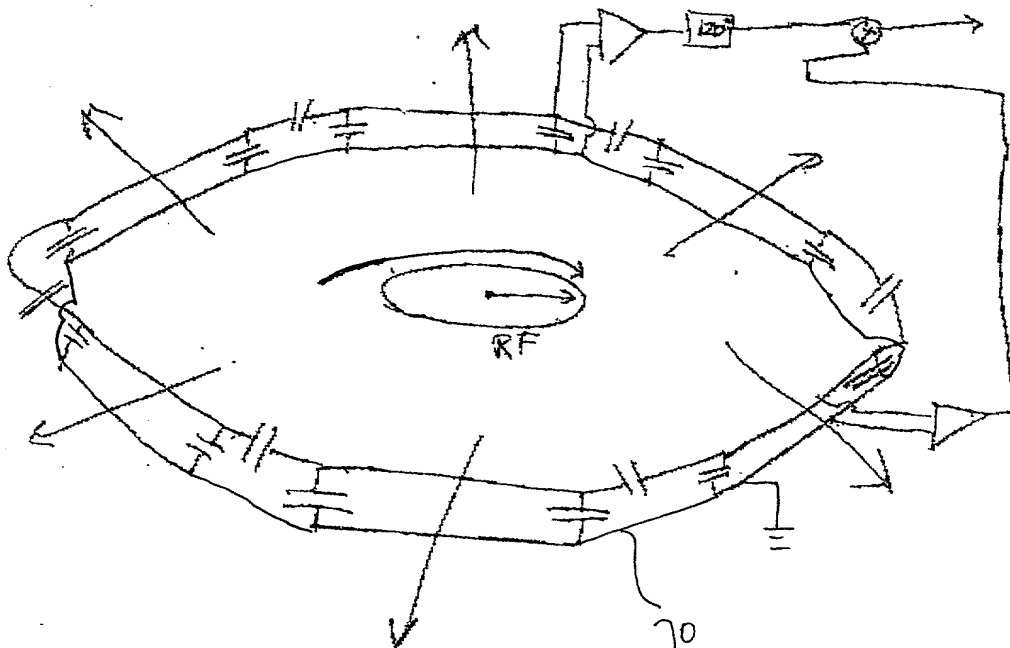


FIG. 7B

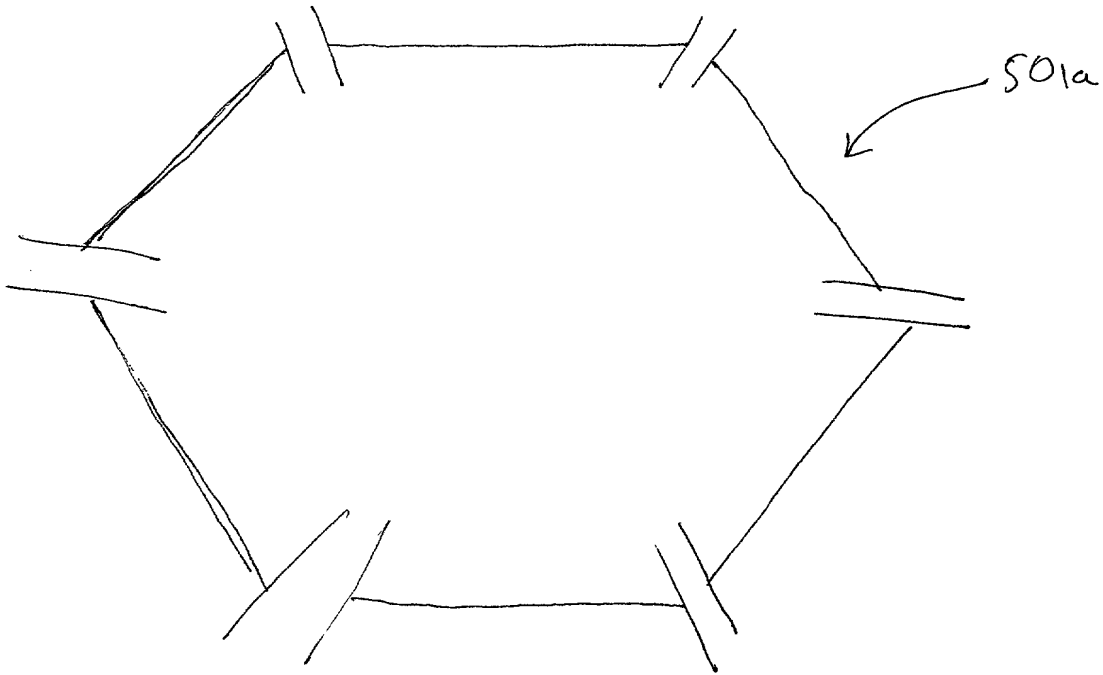


FIG. 8

FIG. 8 is a perspective view of a hexagonal plate 501a having six sides 501b, 501c, 501d, 501e, 501f, and 501g. The plate 501a is shown in a perspective view with break marks on each side to indicate that the plate is of a uniform thickness and shape throughout.

FIG. 9 is a schematic diagram of a device for measuring the magnetic field of a sample. The device includes a sample holder 10, a magnetic field source 20, and a detector 30. The sample holder 10 is a cylindrical container with a grid of holes 12. The magnetic field source 20 is a coil of wire 22 that surrounds the sample holder 10. The detector 30 is a probe 32 that is inserted into one of the holes 12. The probe 32 is connected to a meter 34. The meter 34 is connected to a power source 36. The power source 36 is connected to the magnetic field source 20. The device is used to measure the magnetic field of a sample by measuring the deflection of the probe 32.

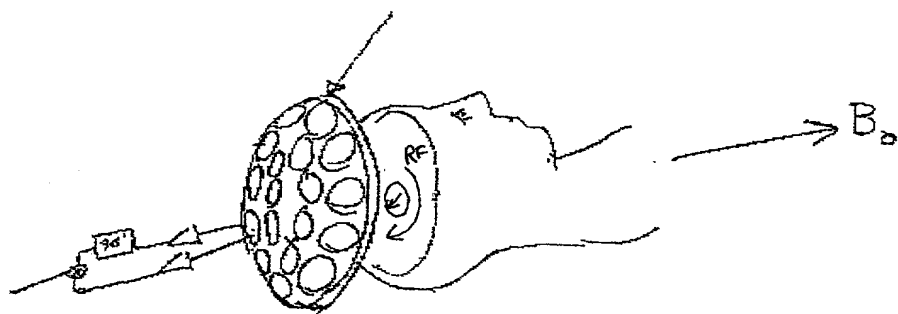


FIG. 9